

FIG. 1A

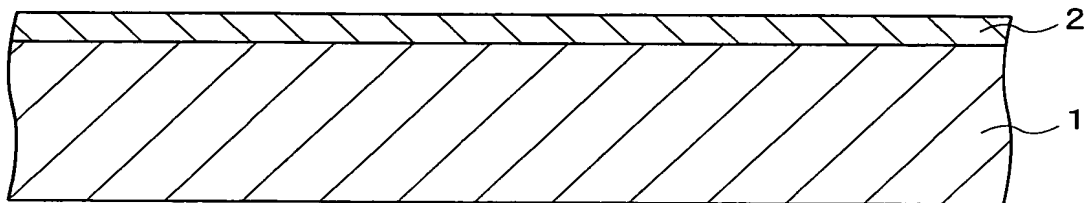


FIG. 1B

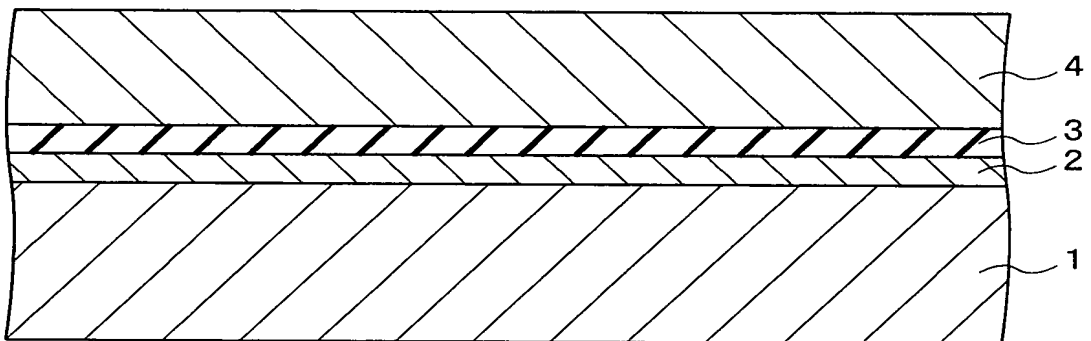


FIG. 1C

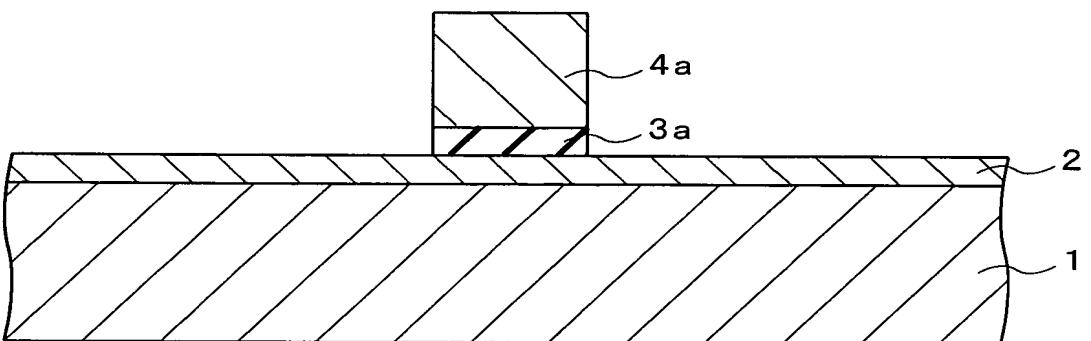


FIG. 2A

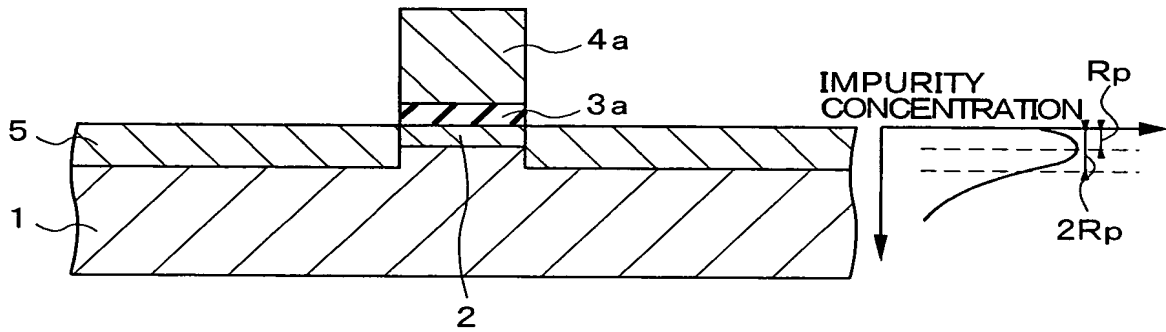


FIG. 2B

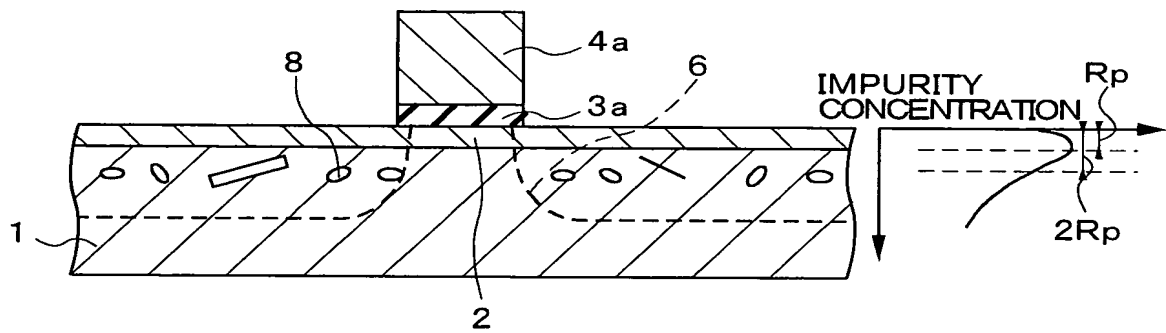


FIG. 2C

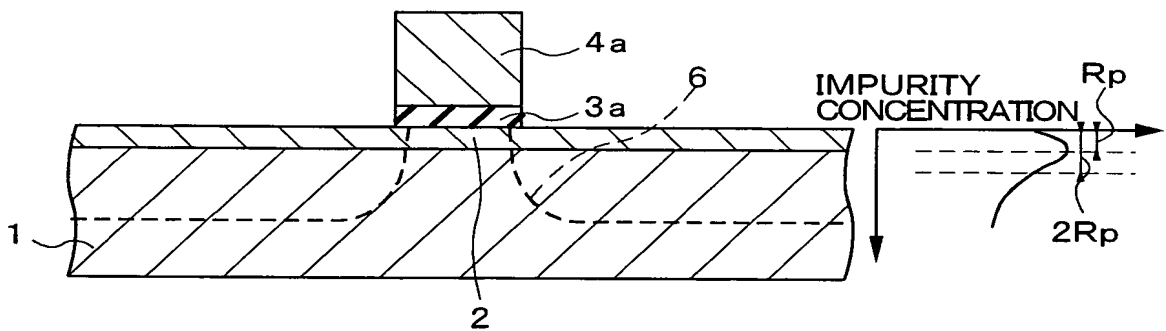


FIG. 3A

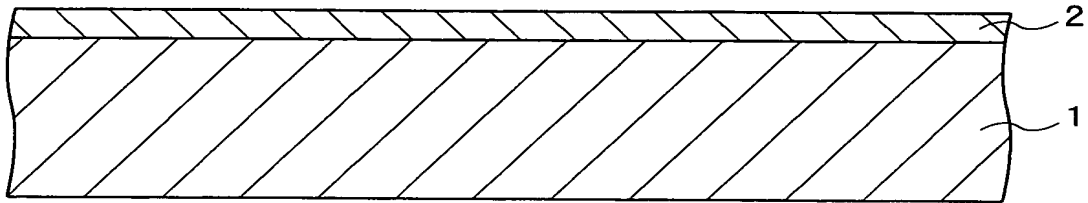


FIG. 3B

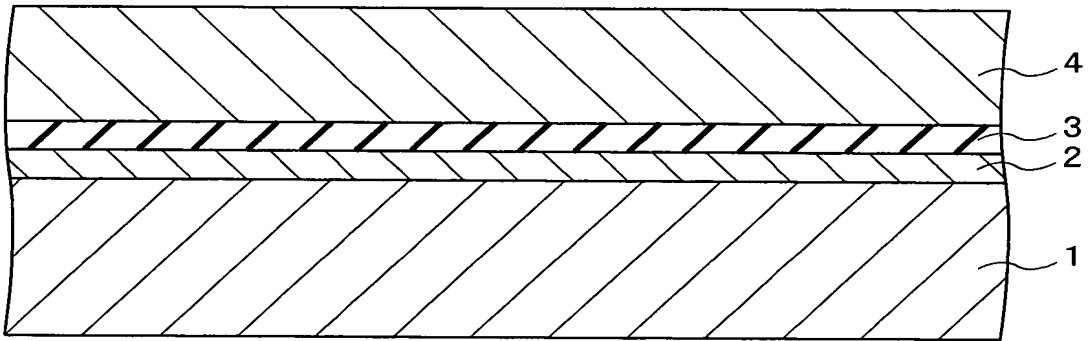


FIG. 3C

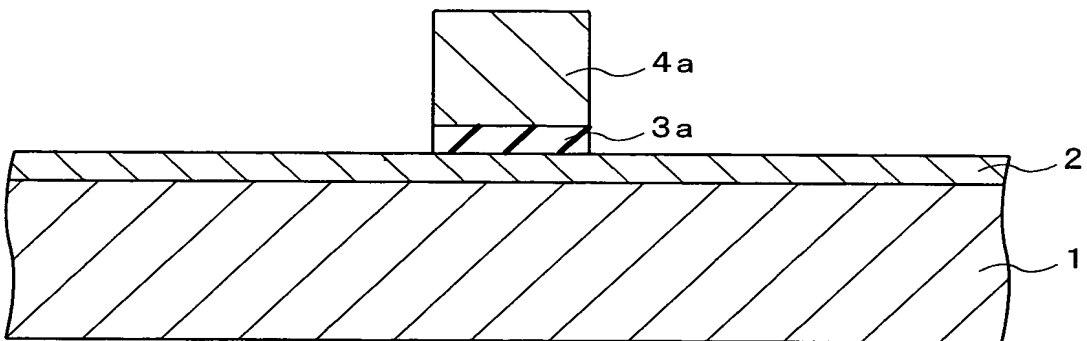


FIG. 4A

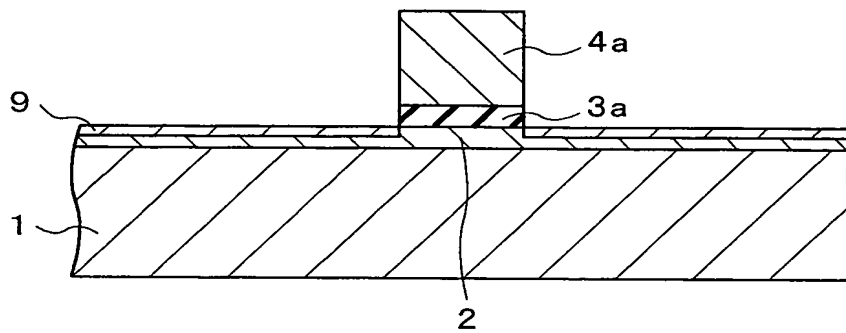


FIG. 4B

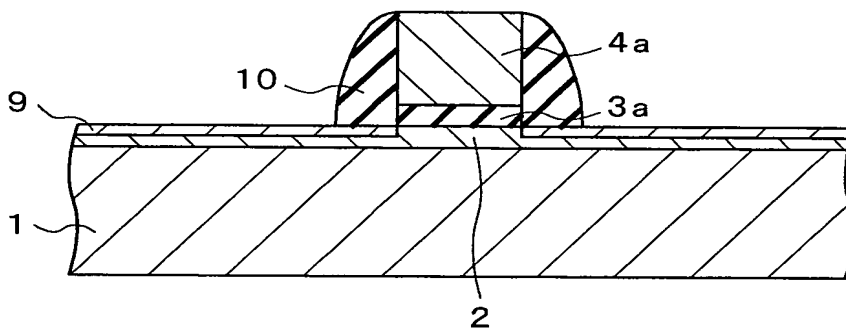


FIG. 4C

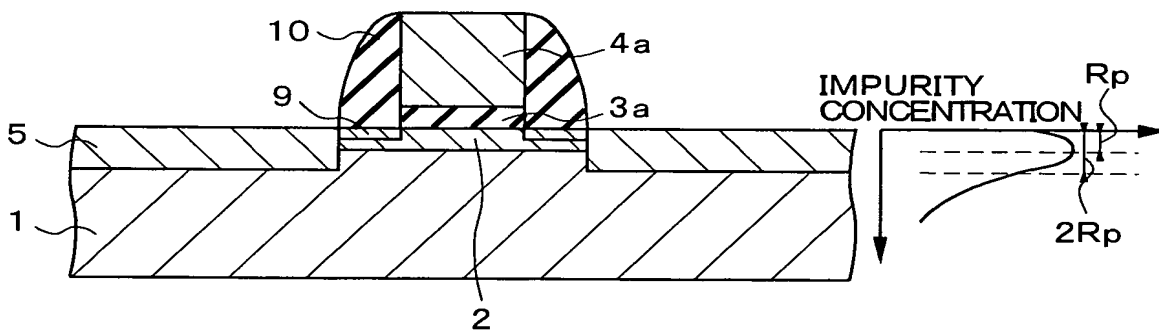


FIG. 5A

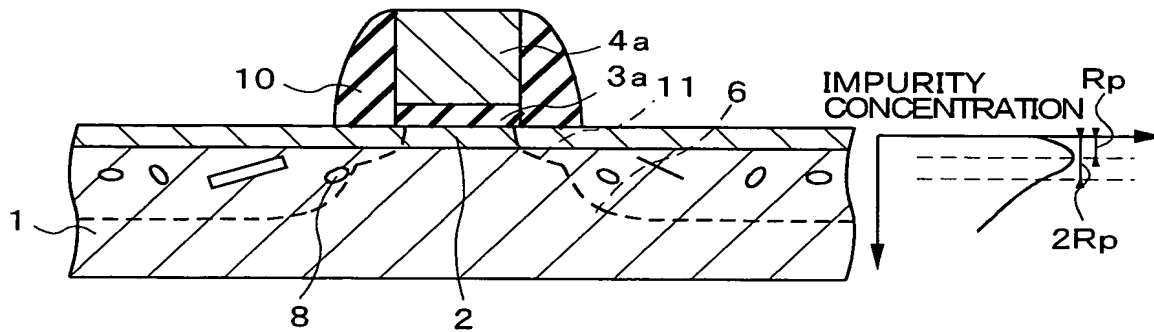


FIG. 5B

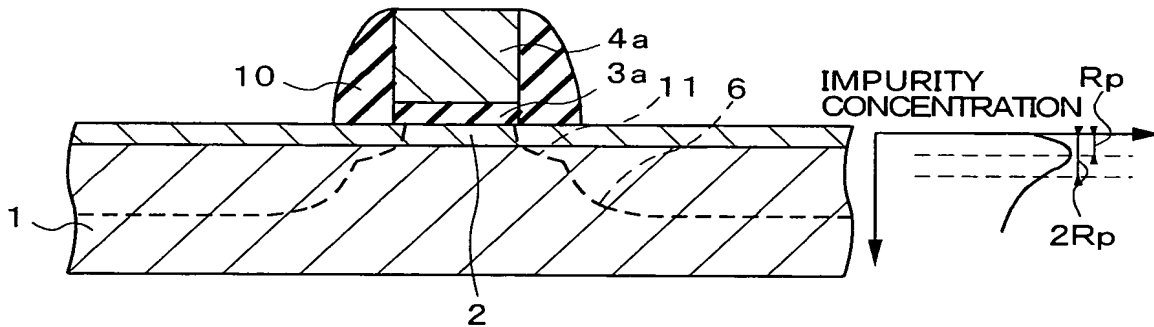


FIG. 6

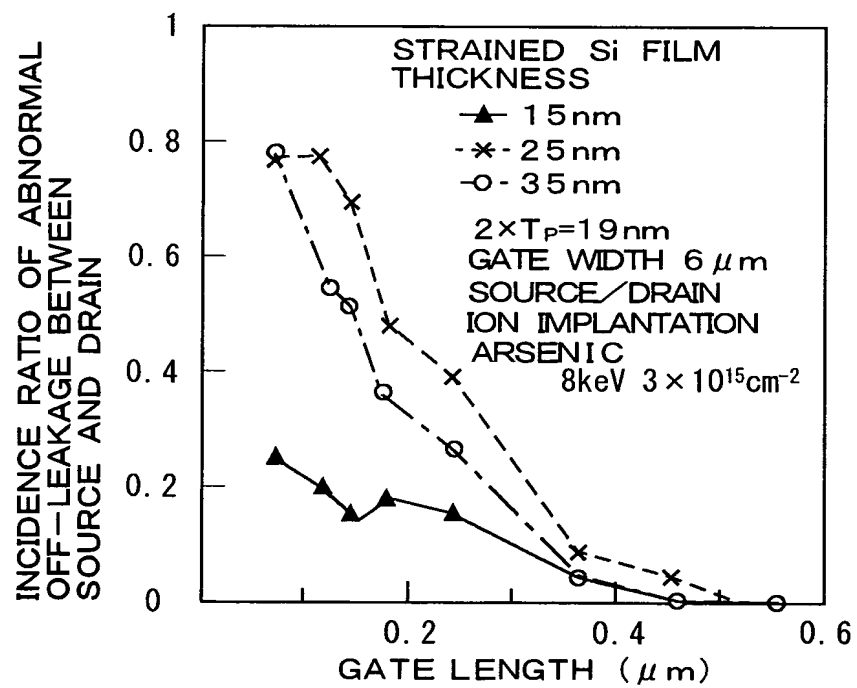


FIG. 7A

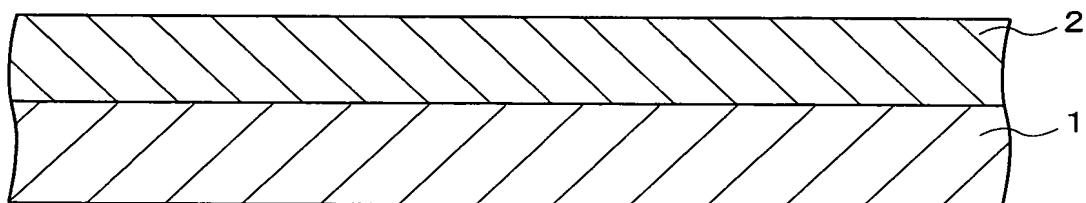


FIG. 7B

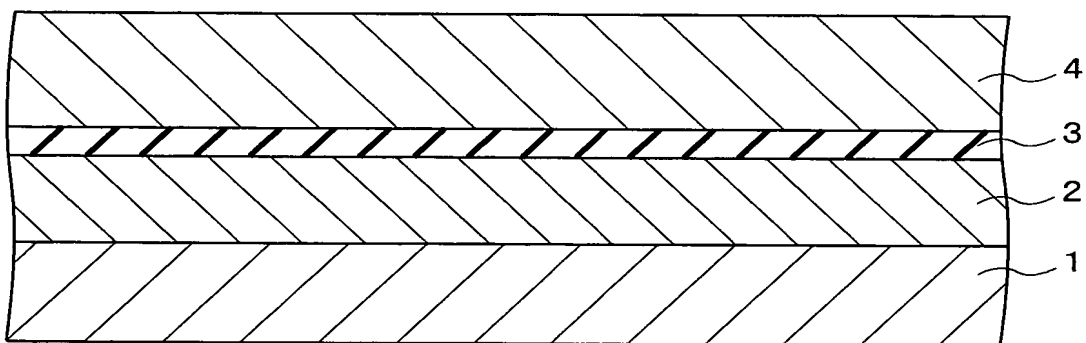


FIG. 7C

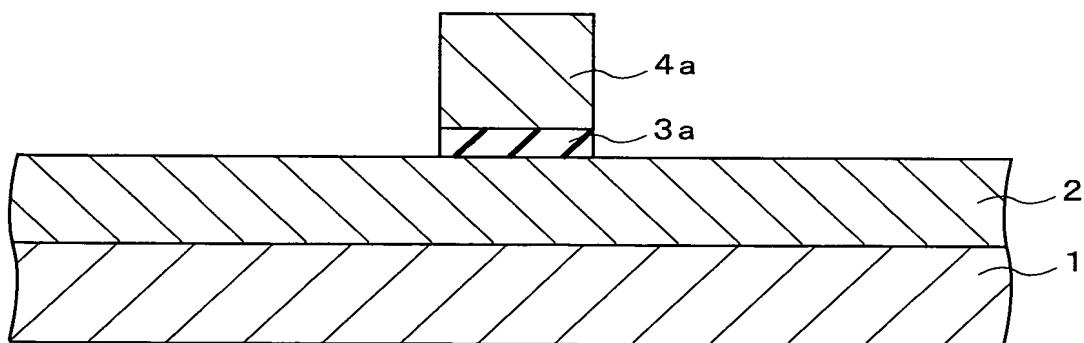


FIG. 8A

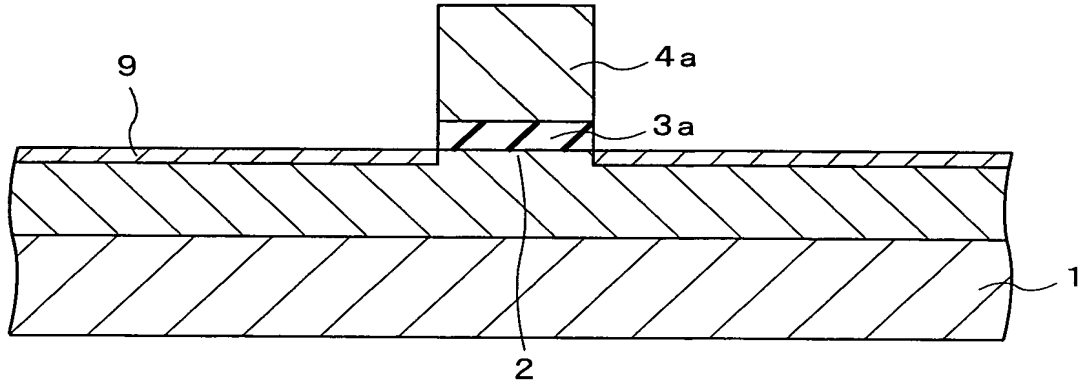


FIG. 8B

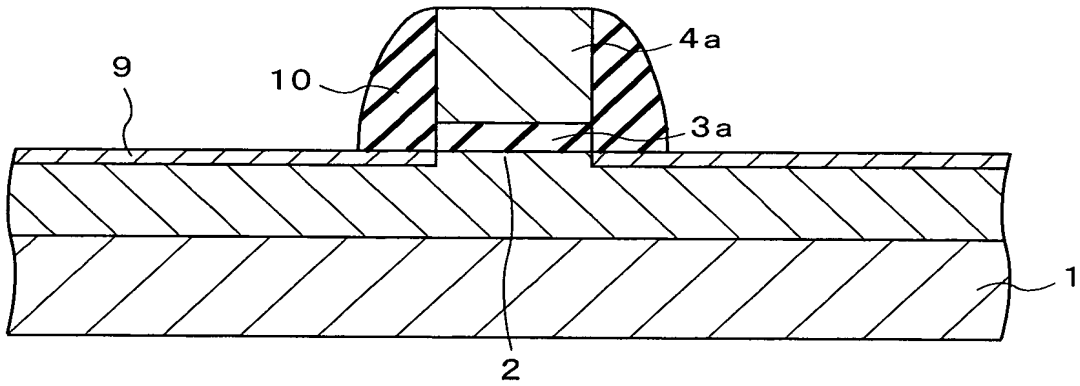


FIG. 8C

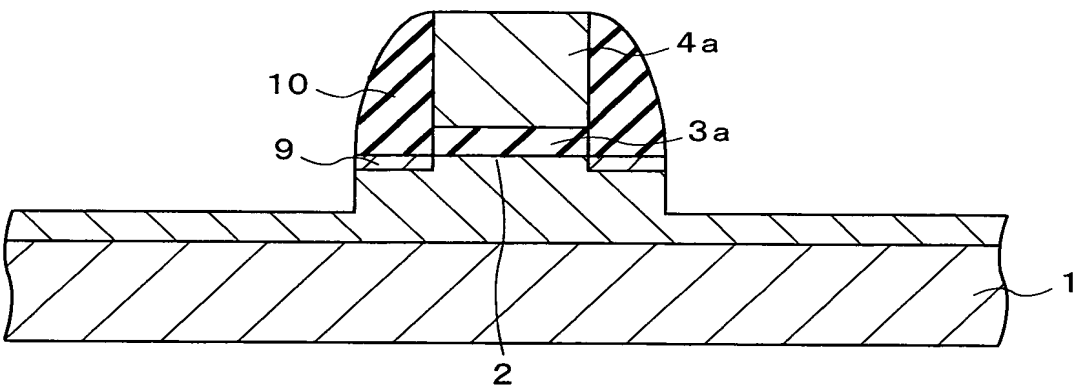


FIG. 9A

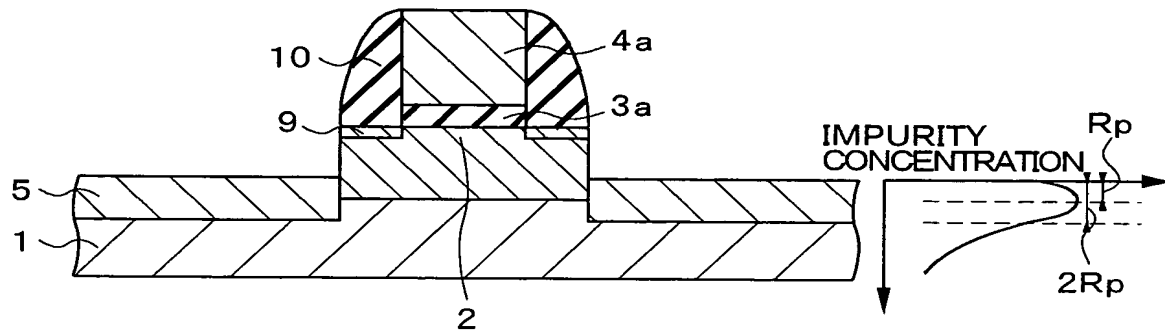


FIG. 9B

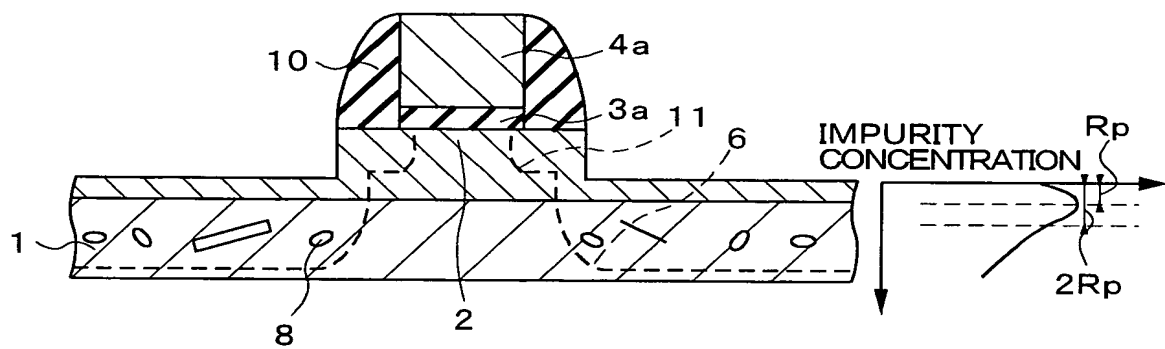


FIG. 9C

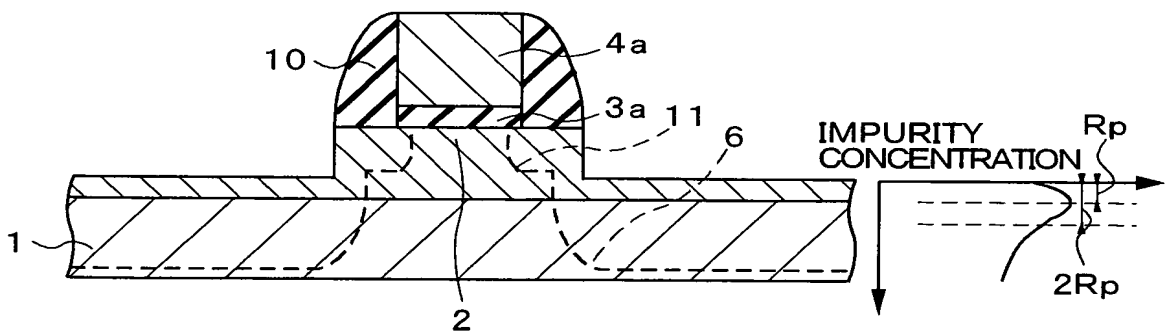


FIG. 10A

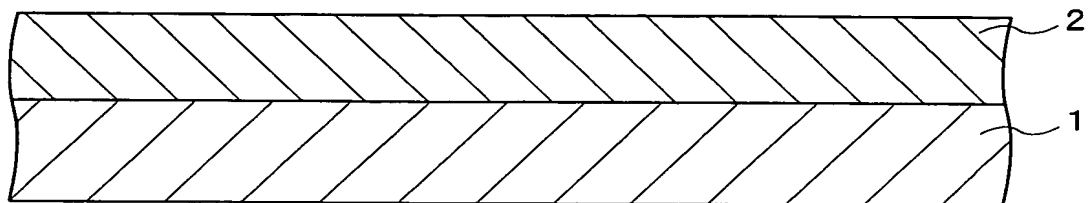


FIG. 10B

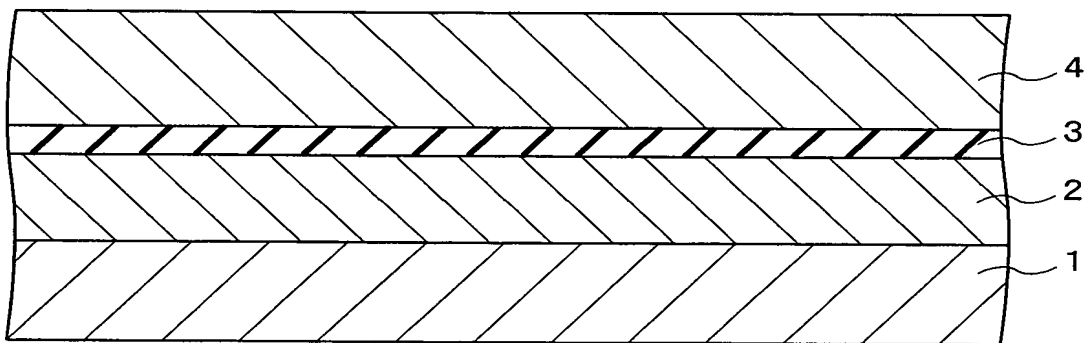


FIG. 10C

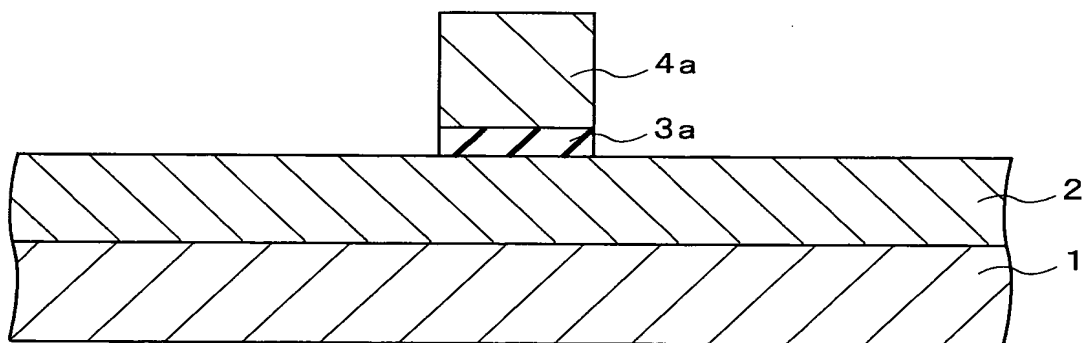


FIG. 11A

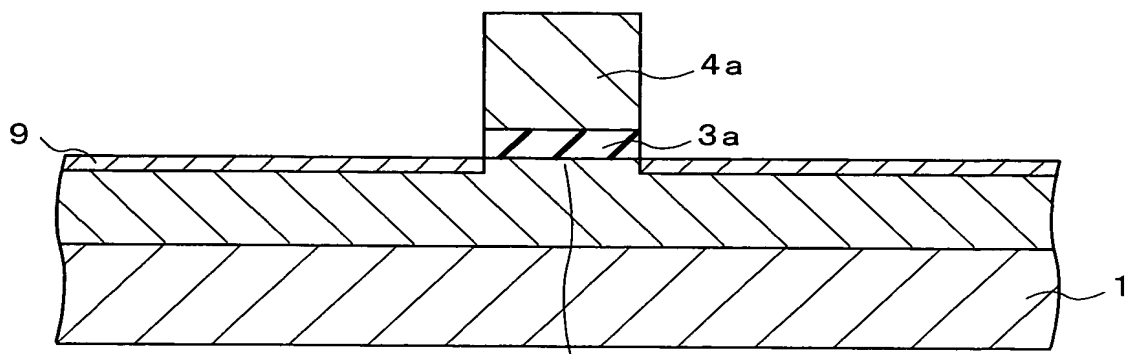


FIG. 11B

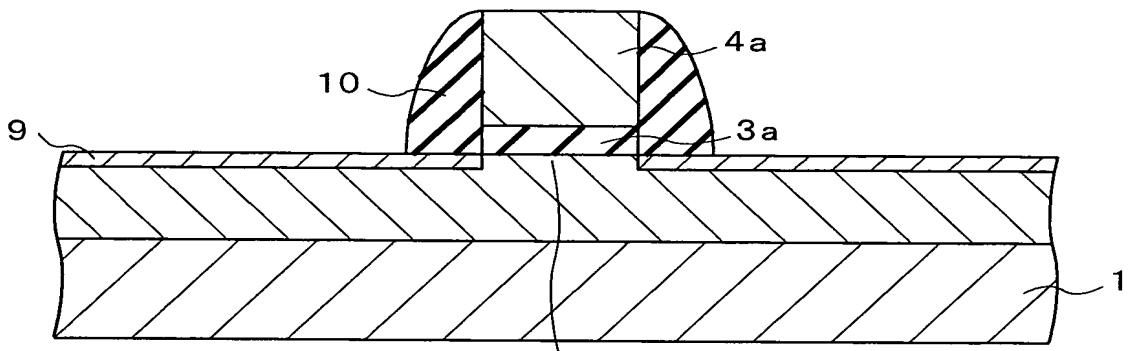


FIG. 11C

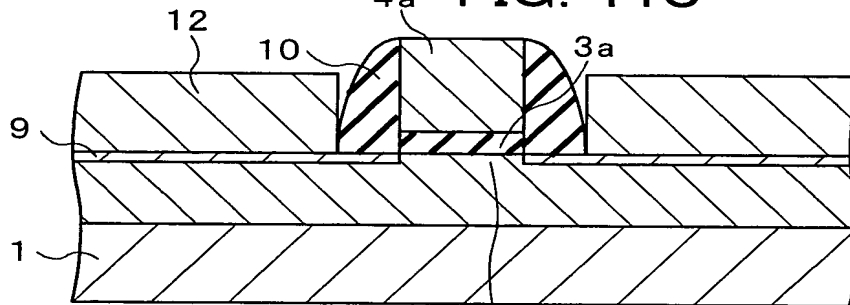
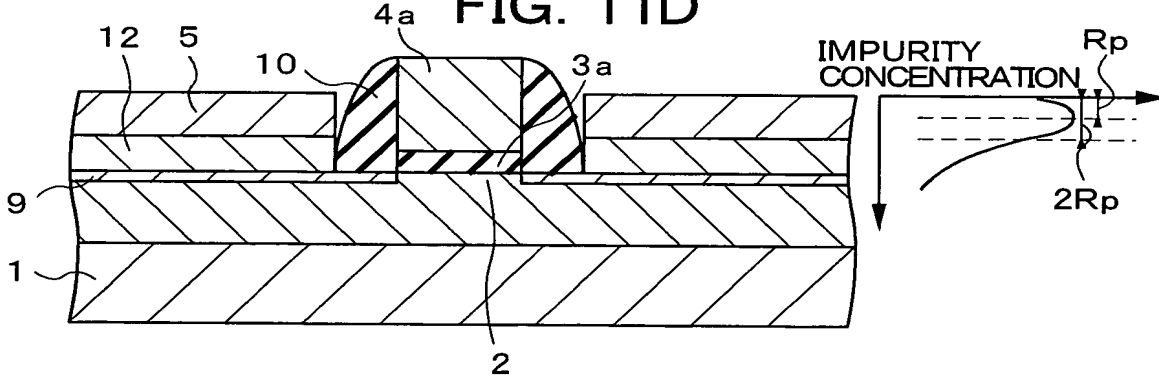


FIG. 11D



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FIG. 12A

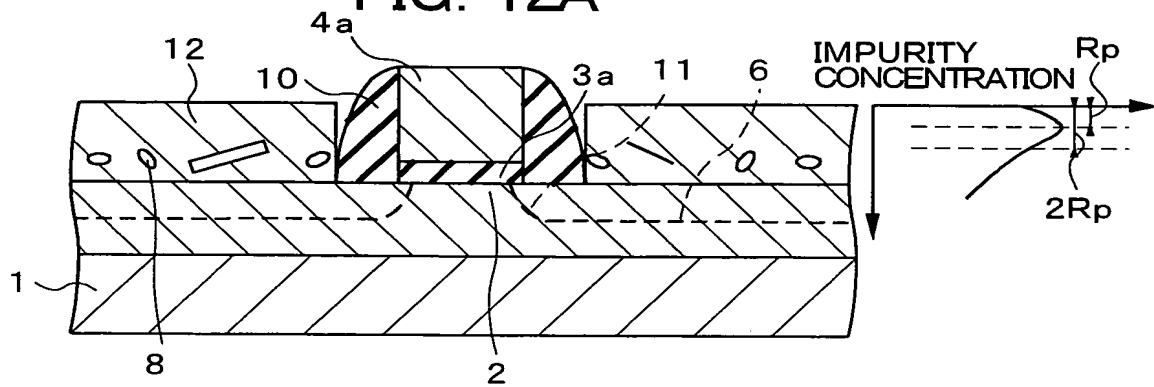


FIG. 12B

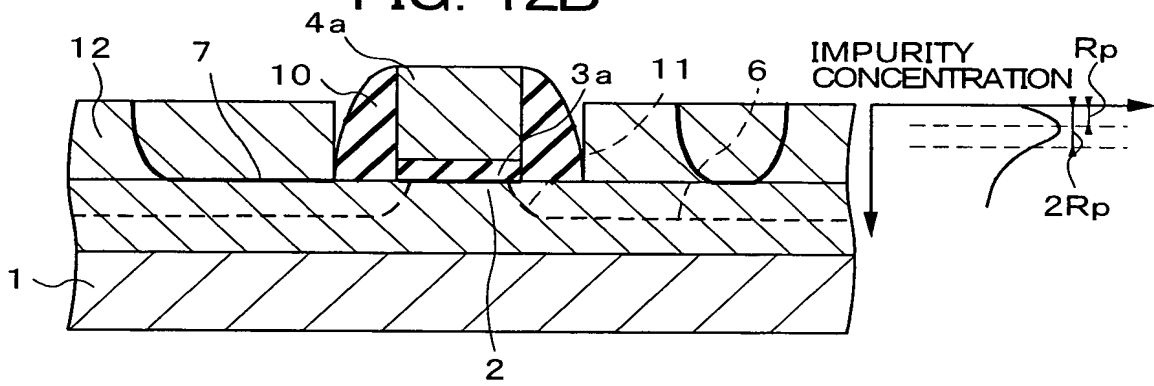


FIG. 13

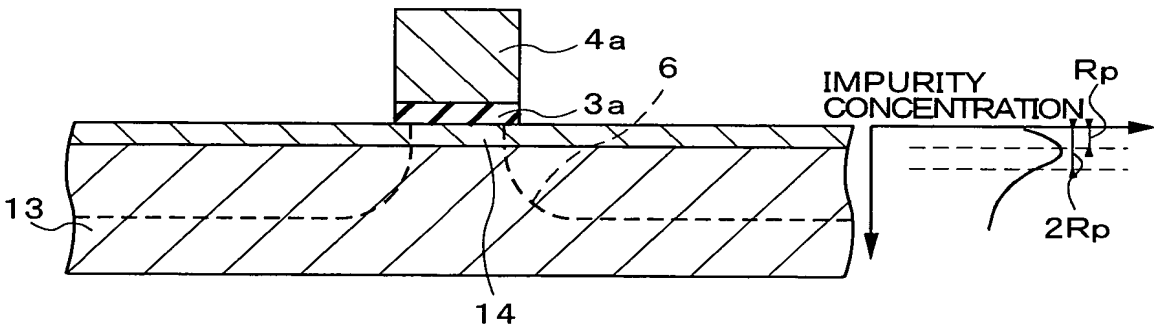


FIG. 14

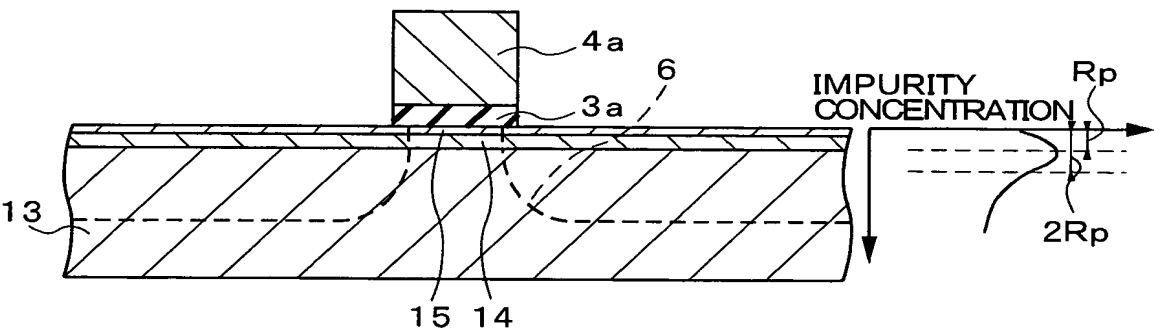


FIG. 15

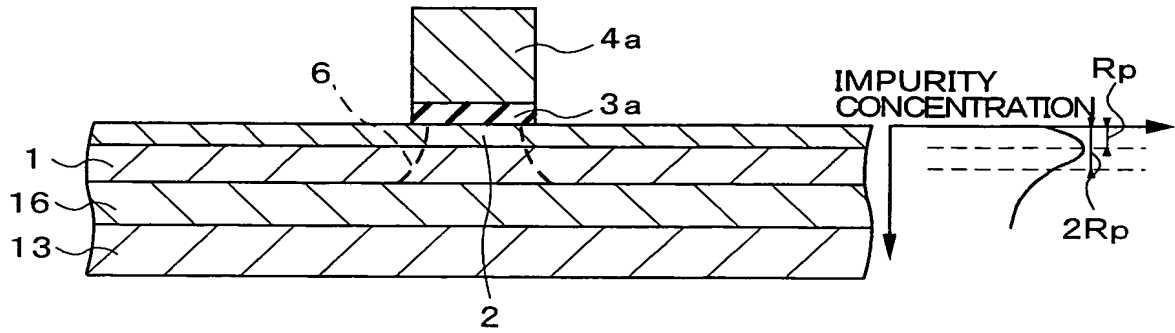


FIG. 16

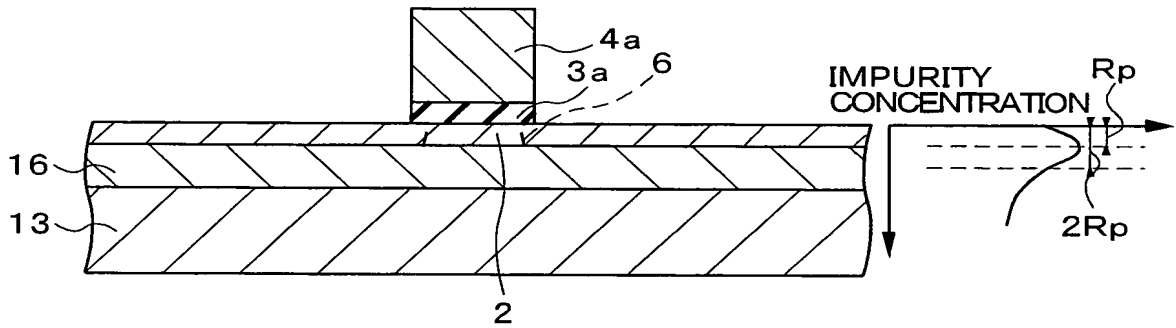


FIG. 17

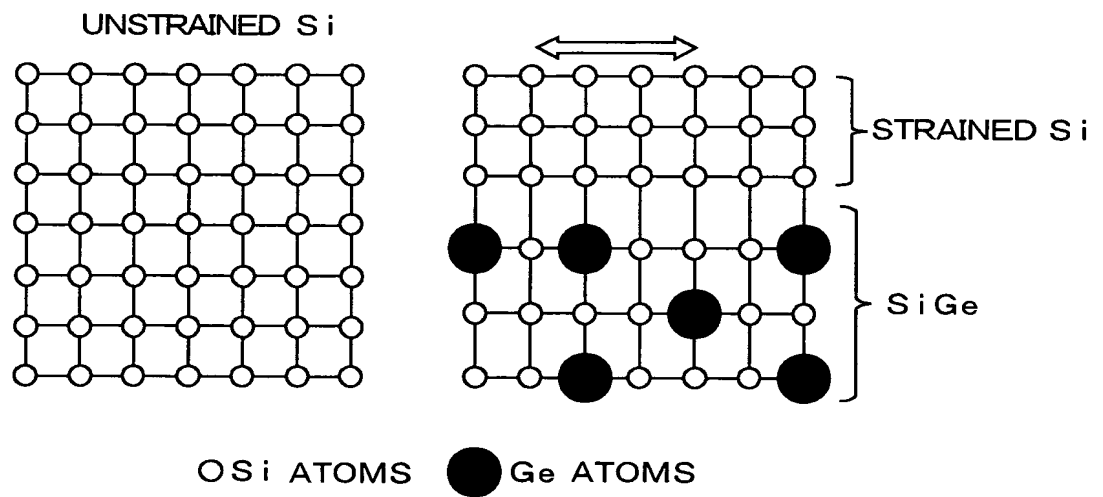


FIG. 18A

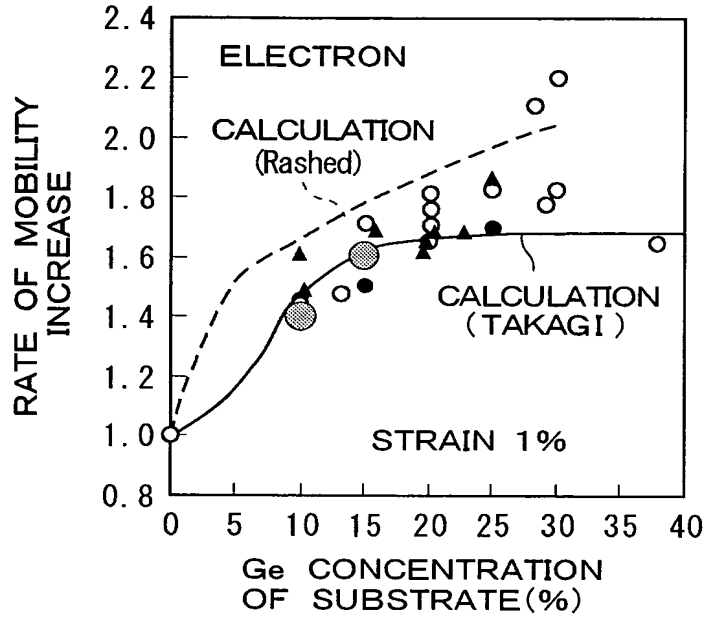


FIG. 18B

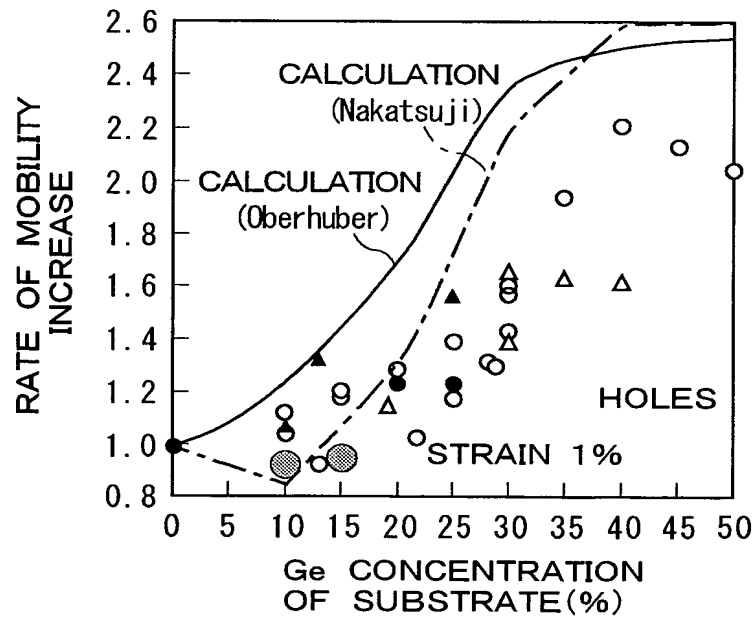


FIG. 19A

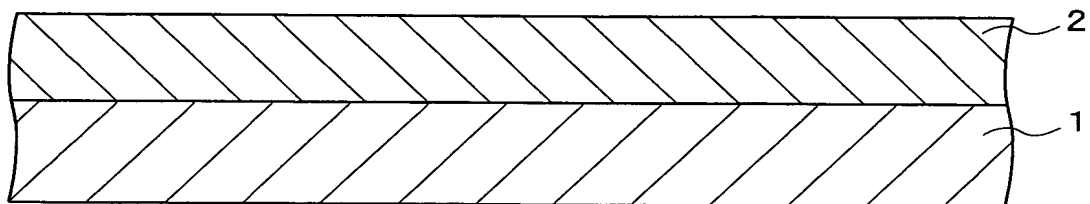


FIG. 19B

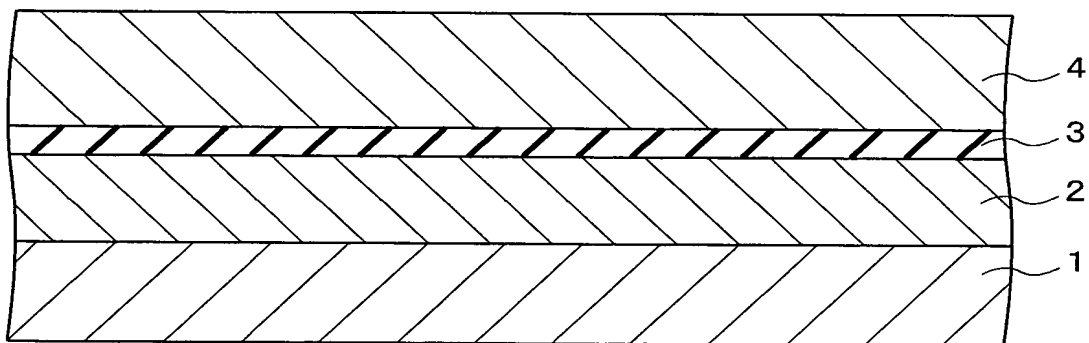
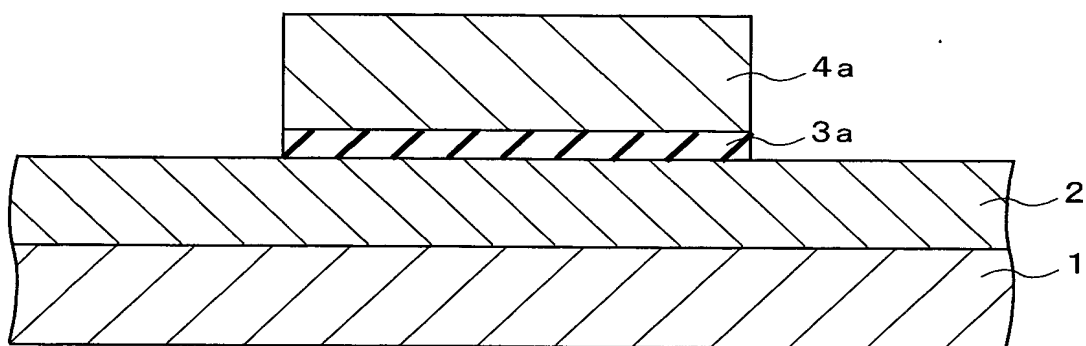


FIG. 19C



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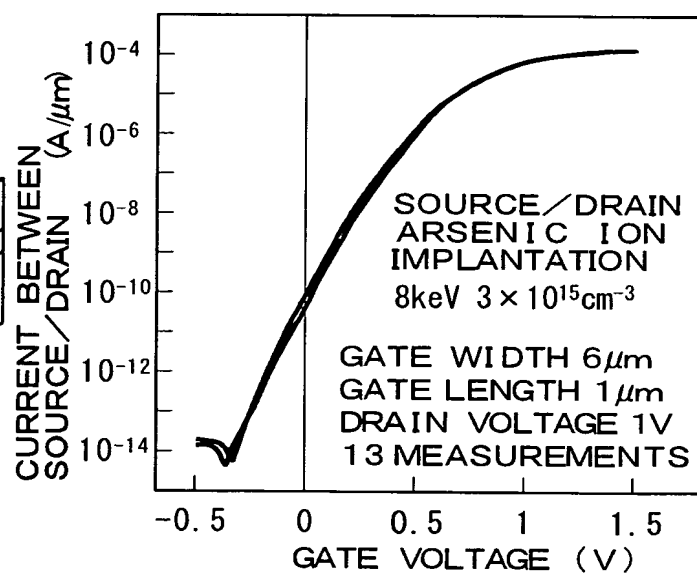


FIG. 22A

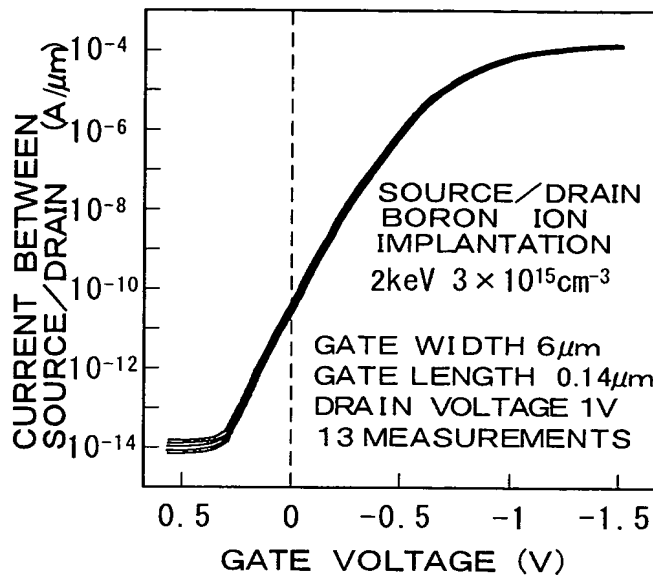


FIG. 22B

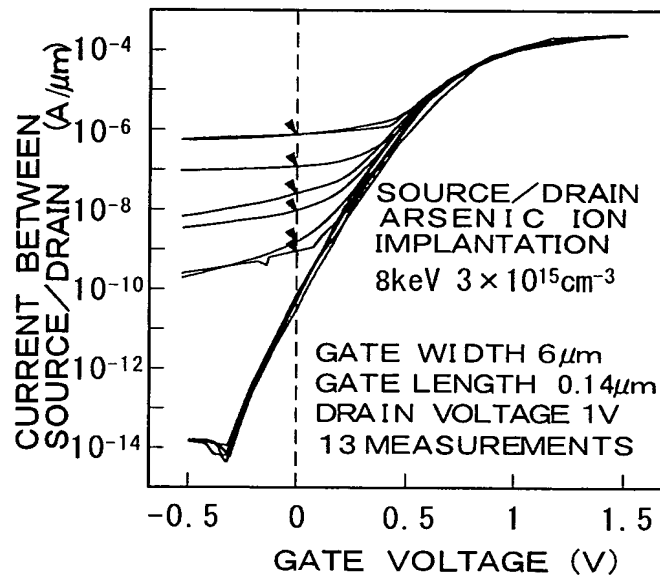
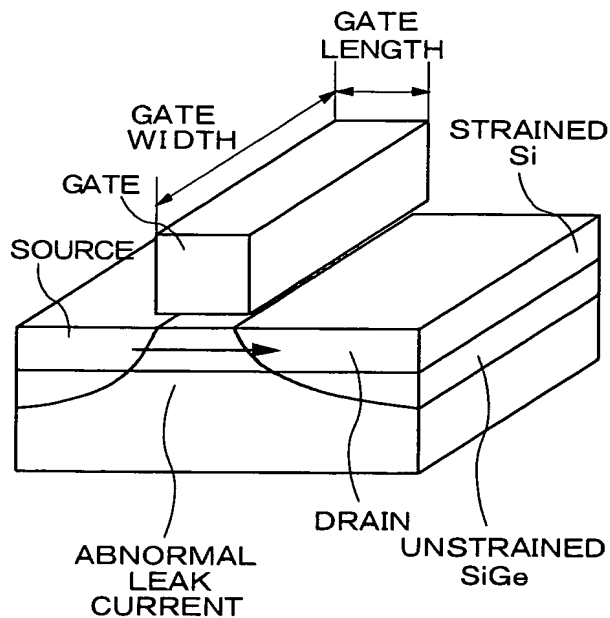


FIG. 23



INCIDENCE RATIO OF
 ABNORMAL OFF-LEAKAGE
 CURRENT BETWEEN
 SOURCE/ DRAIN

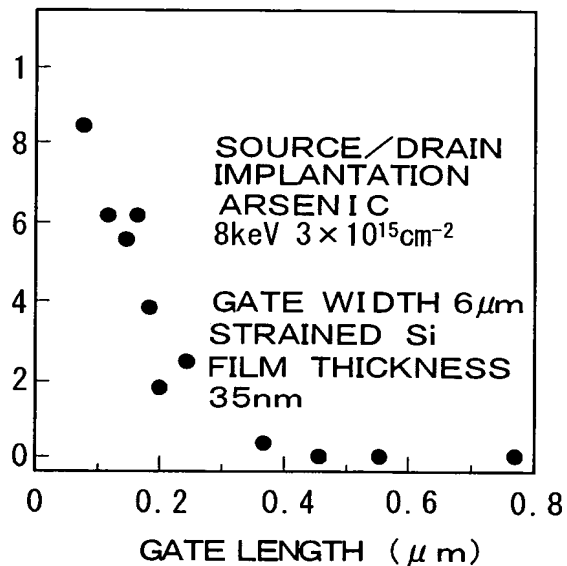
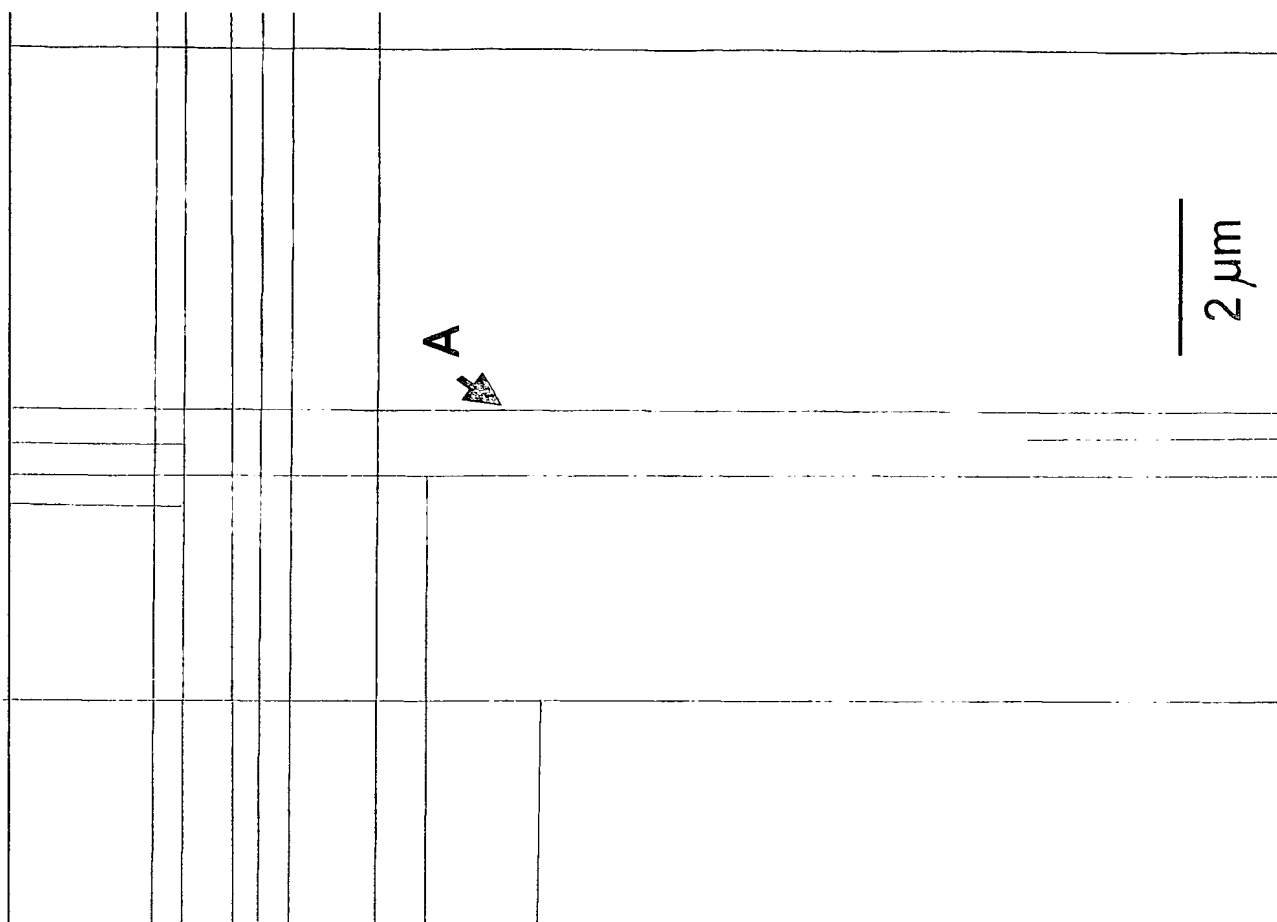


FIG. 24

(a)' PLANAR TEM IMAGE

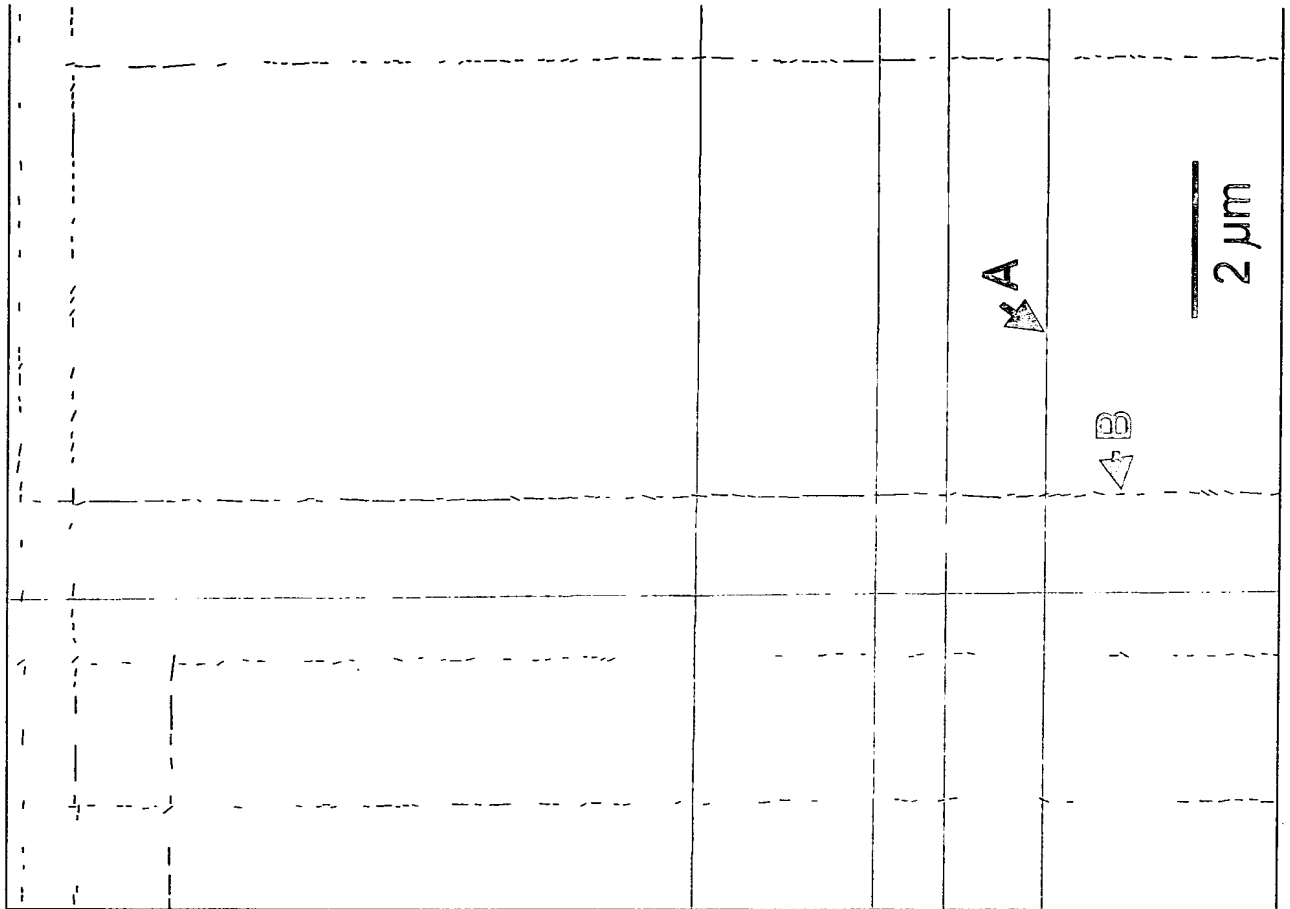


(a) PLANAR TEM IMAGE

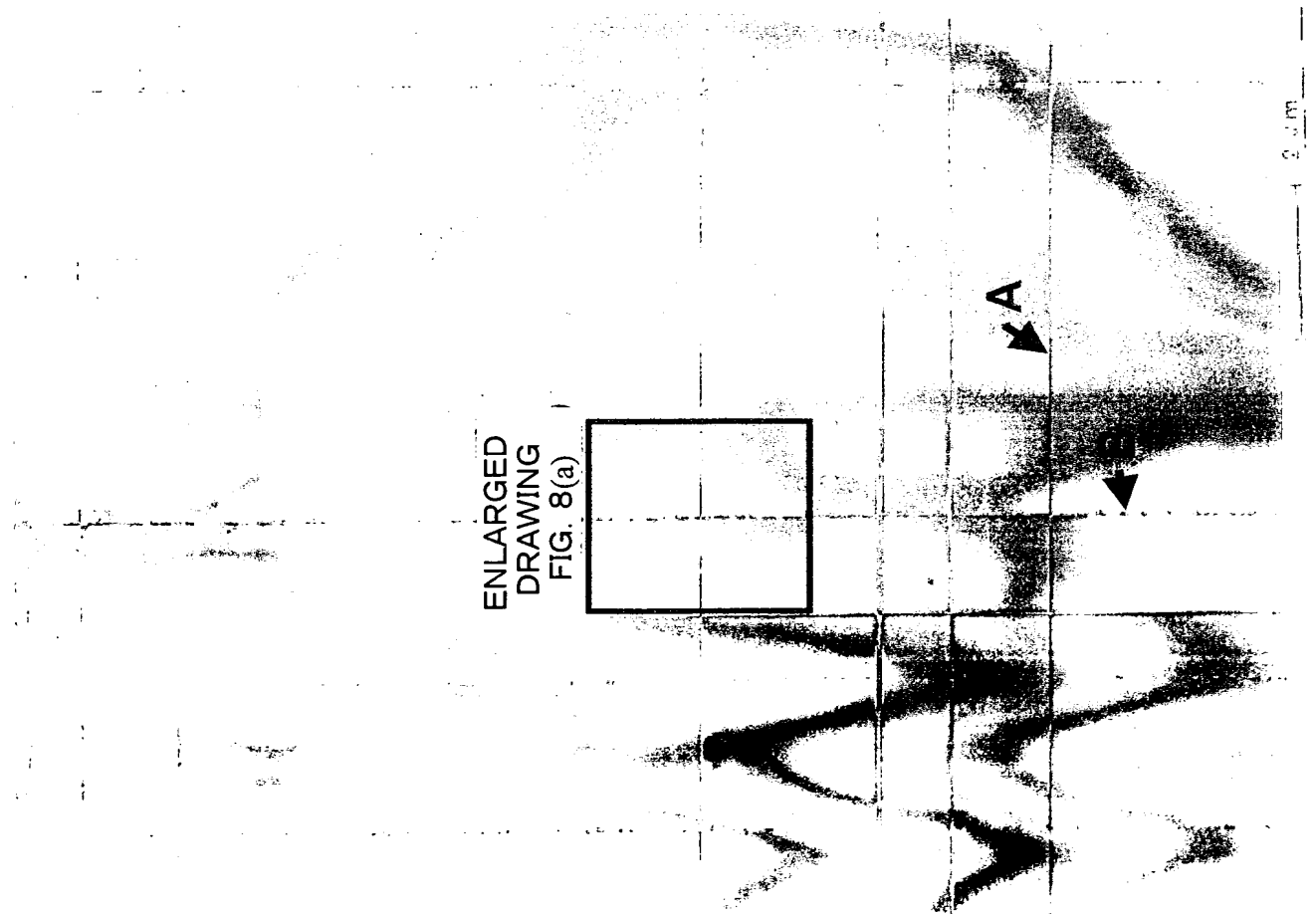


FIG. 24 CONTINUE

(b)' PLANAR TEM IMAGE



(b) PLANAR TEM IMAGE



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FIG. 25

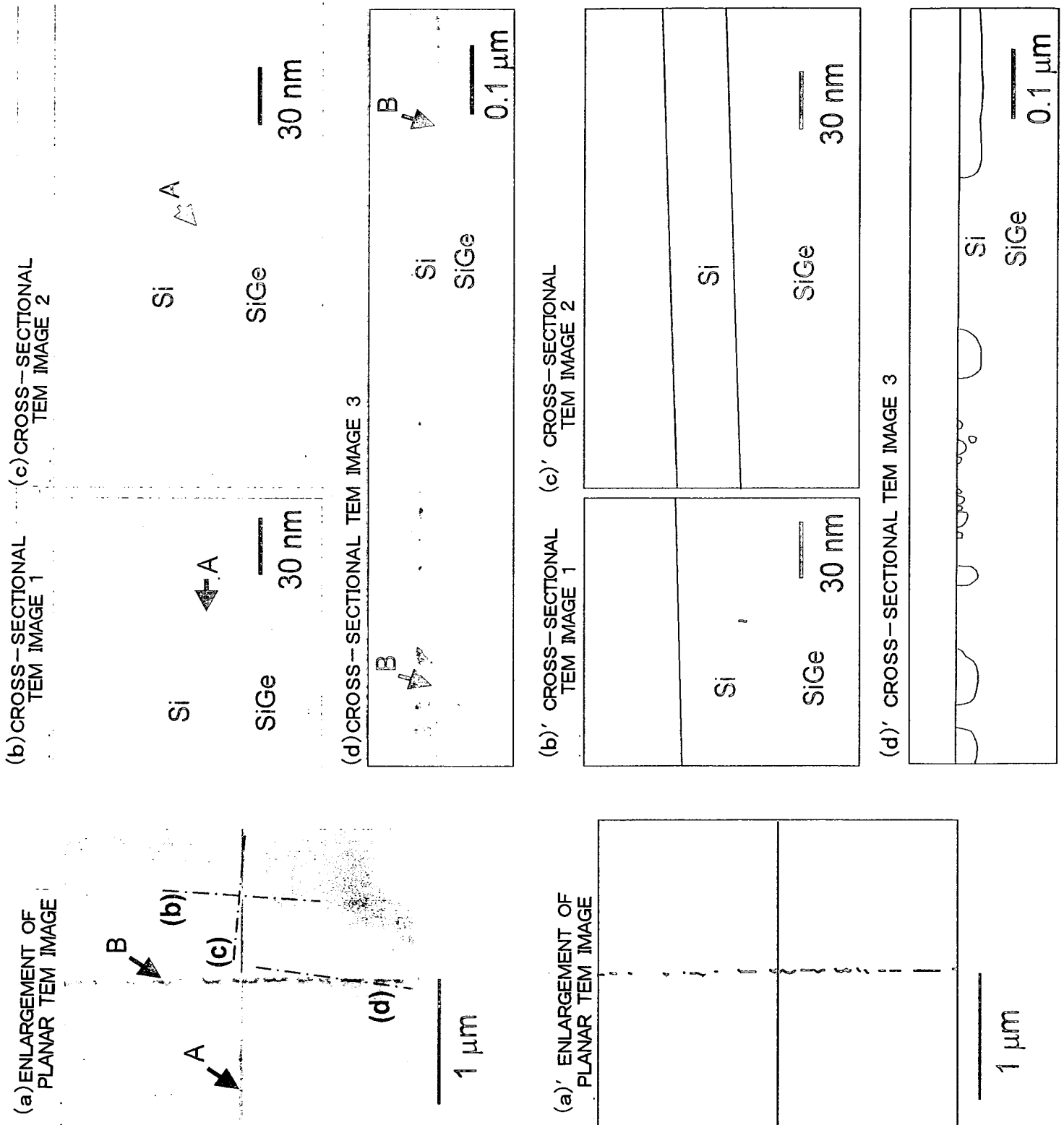
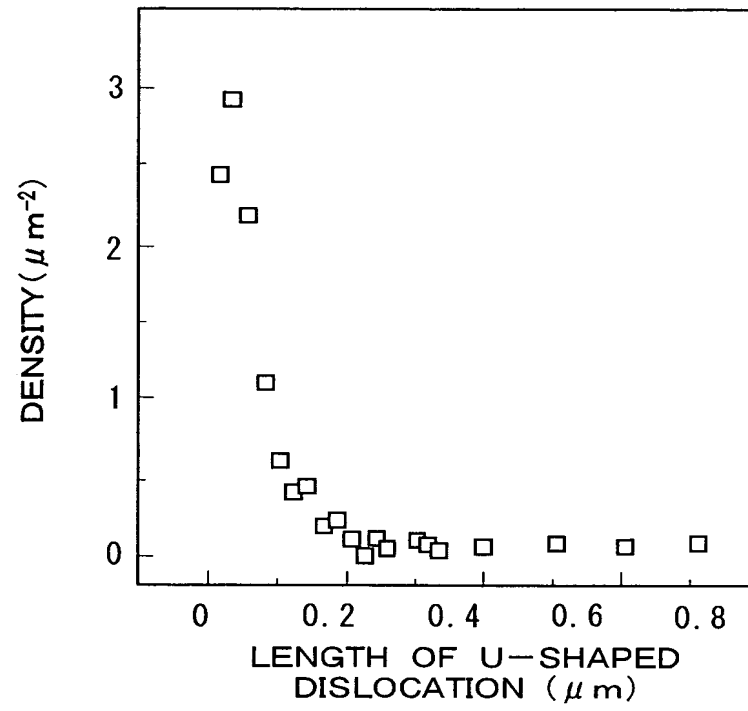


FIG. 26



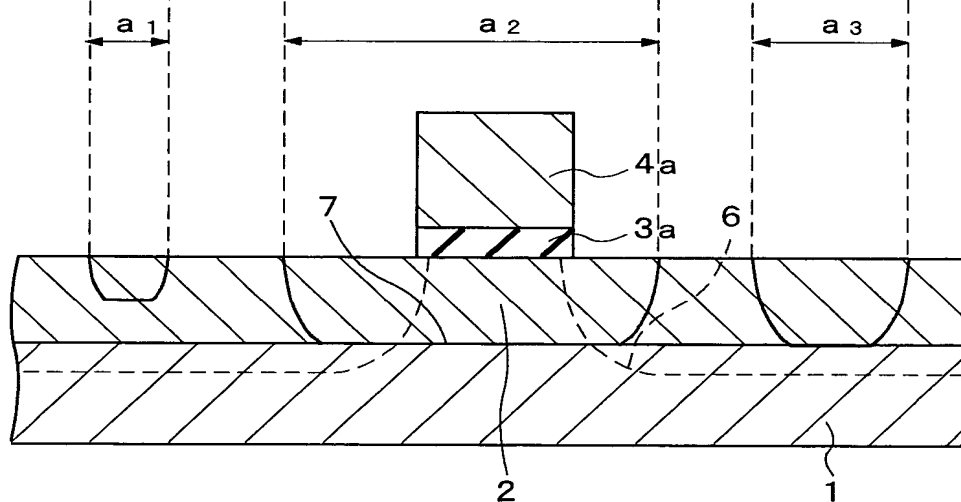
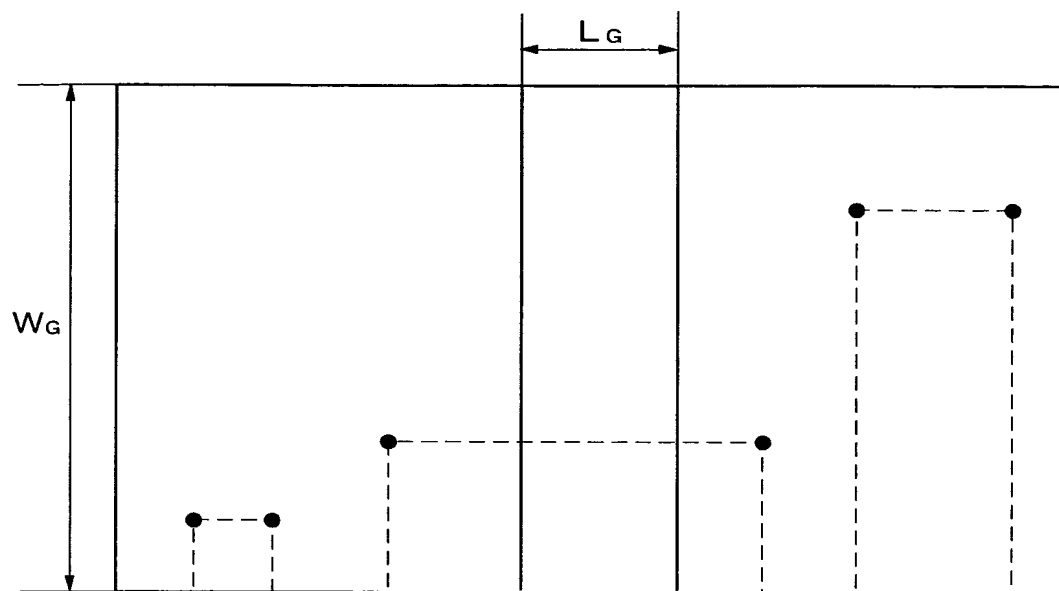


FIG. 28

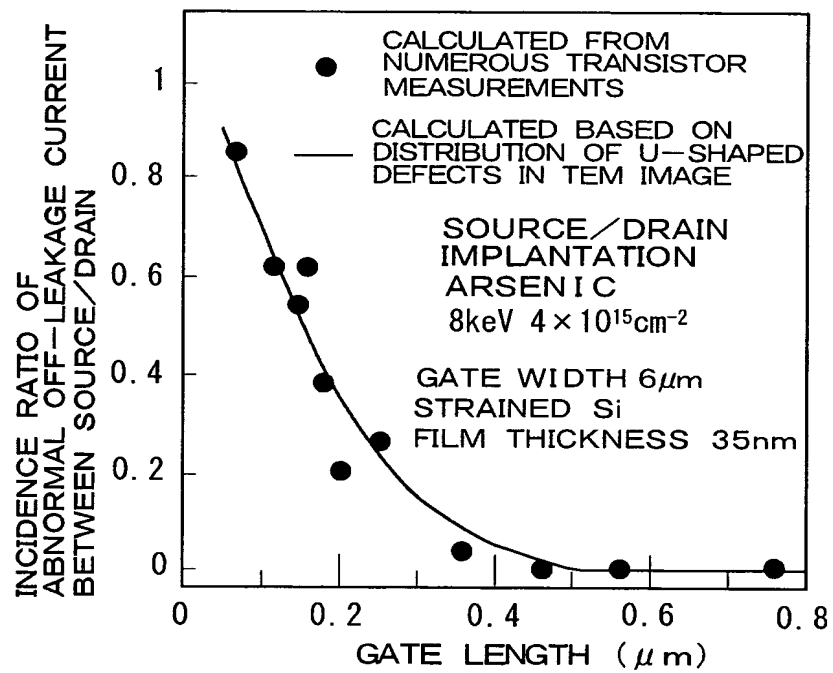
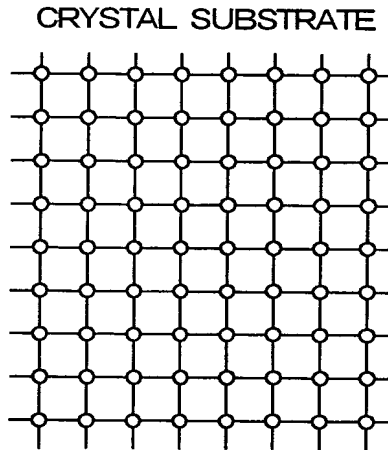


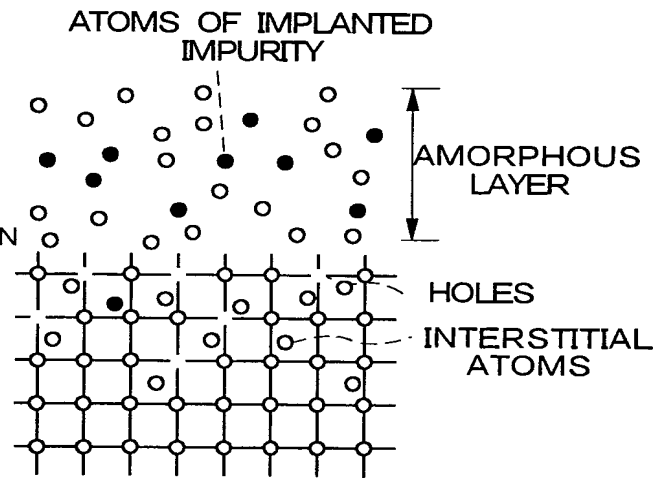
FIG. 29A



ION
IMPLANTATION



FIG. 29C



HEAT
TREATMENT



FIG. 29B

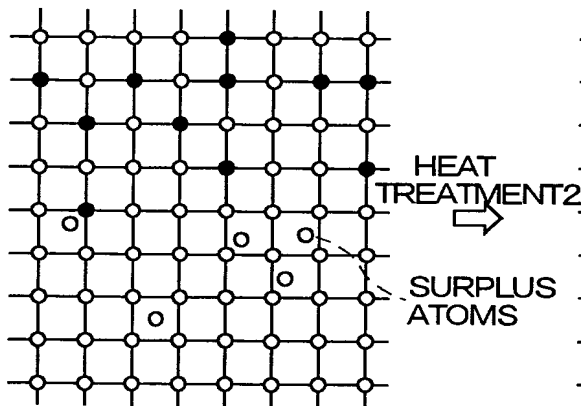


FIG. 29D

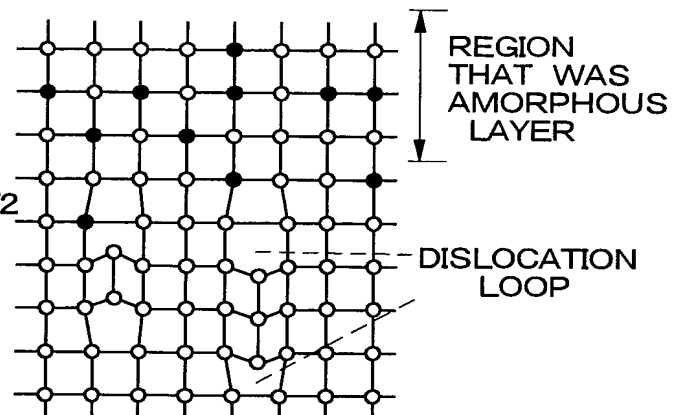


FIG. 30A

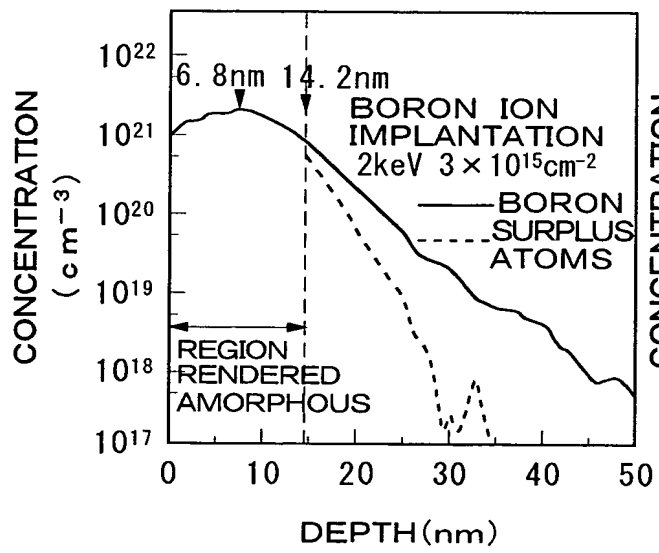


FIG. 30B

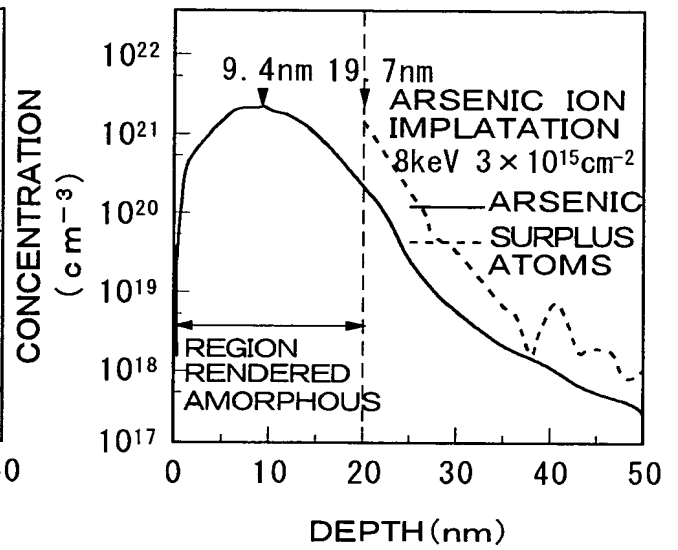


FIG. 31

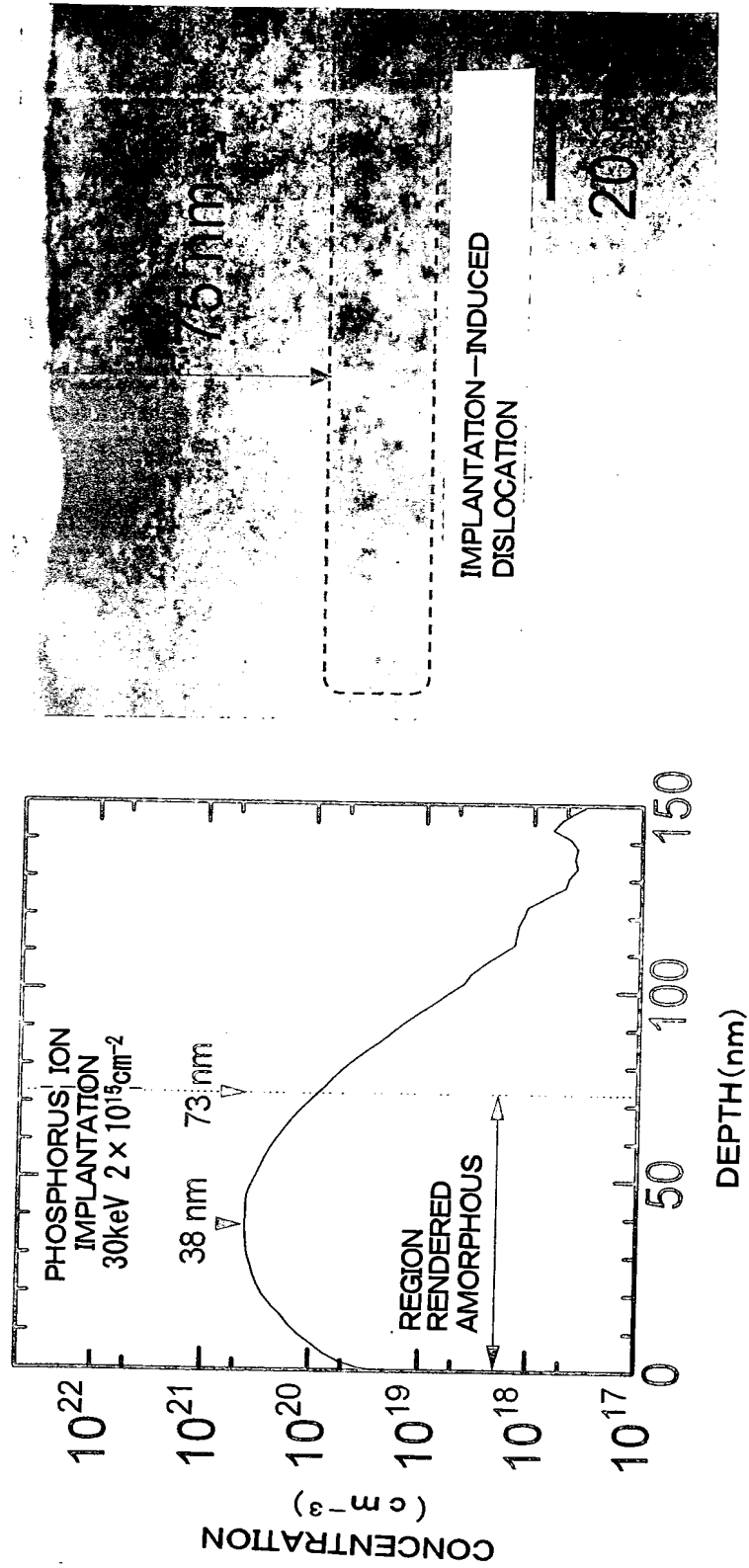
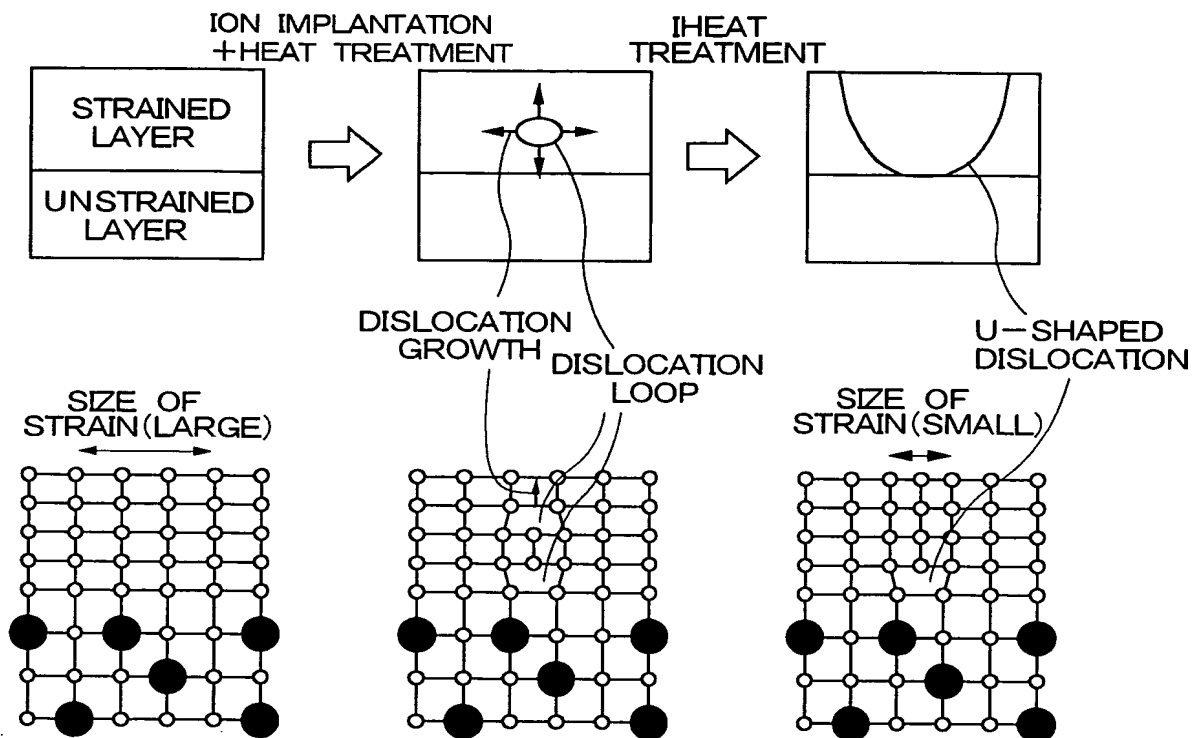


FIG. 32A

FIG. 32B

FIG. 32C



LOWER DIAGRAMS ARE SCHEMATIC VIEWS OF UPPER DIAGRAMS
 WHEN THE UPPER DIAGRAMS ARE VIEWED DIRECTLY FROM THE SIDE

FIG. 33

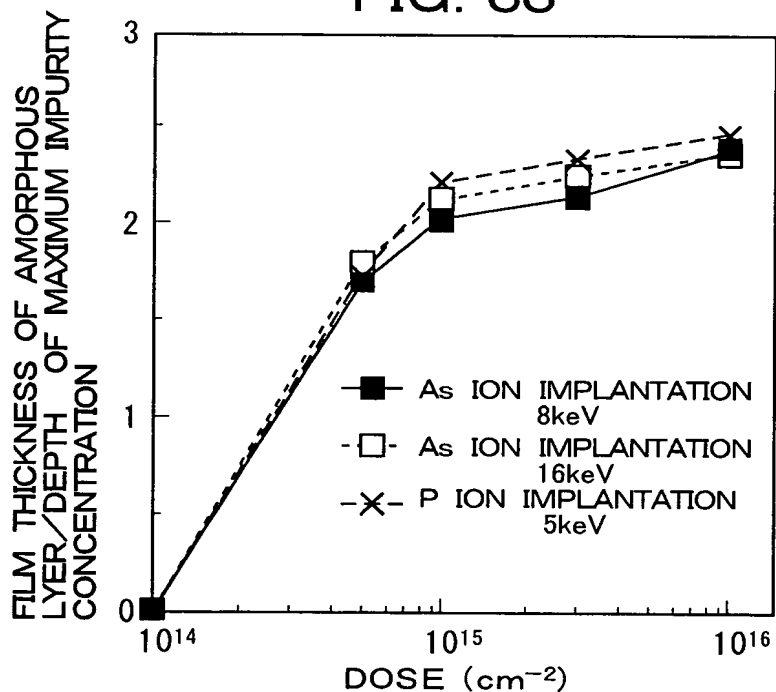


FIG. 34A

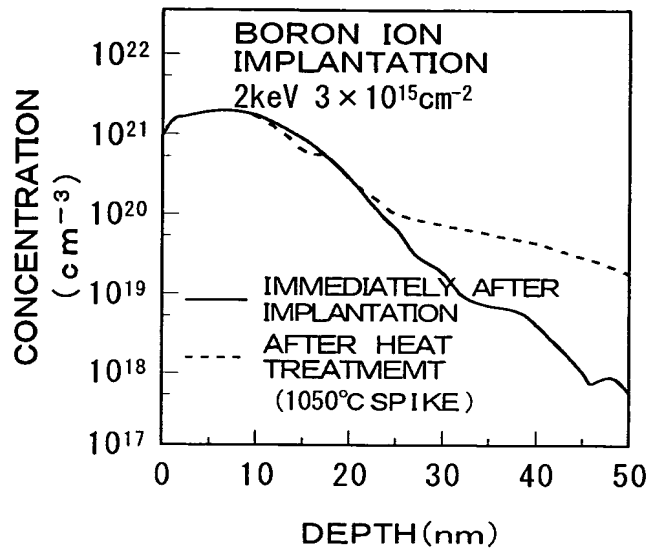


FIG. 34B

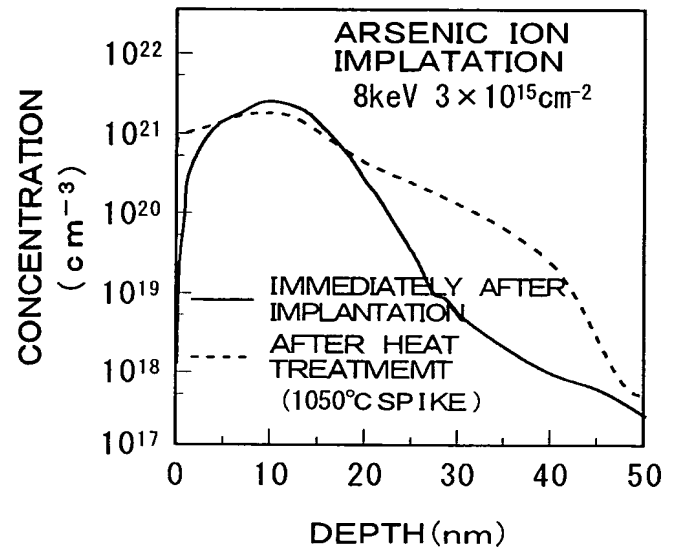


FIG. 35A

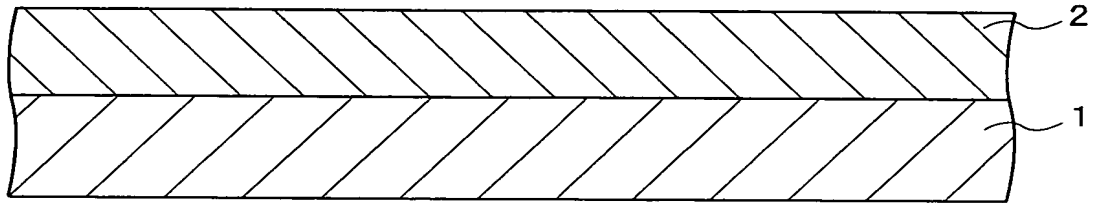


FIG. 35B

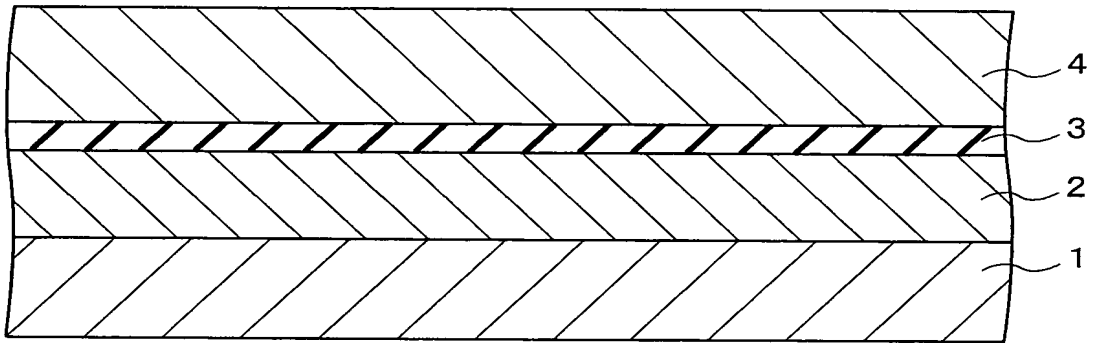


FIG. 35C

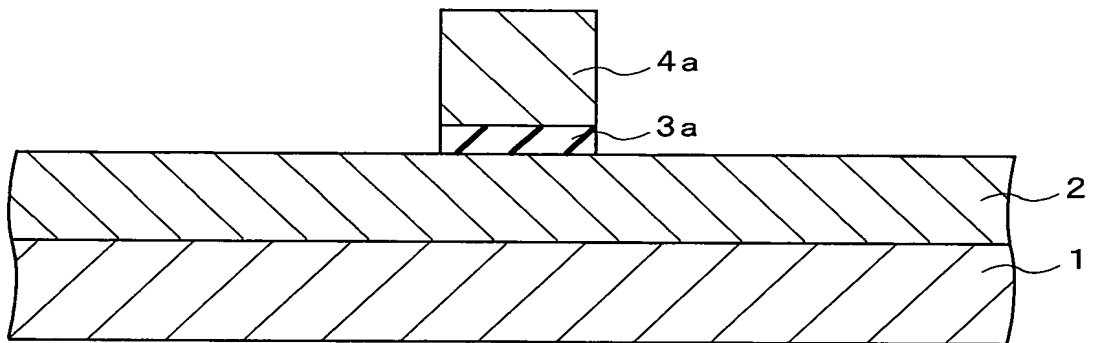


FIG. 36A

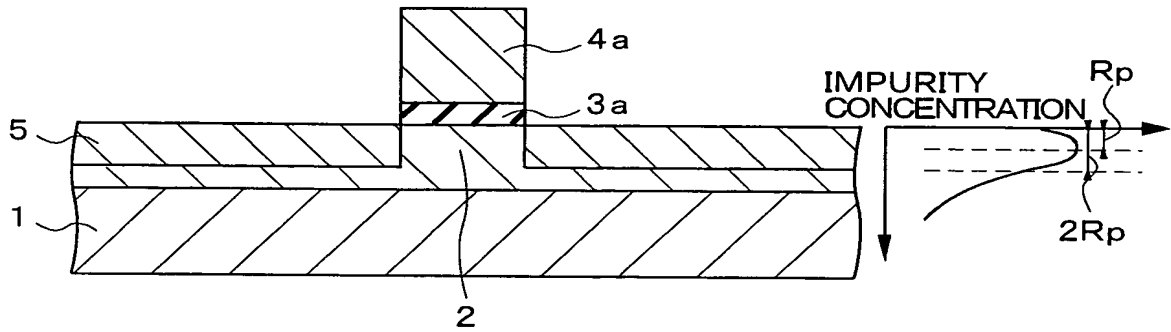


FIG. 36B

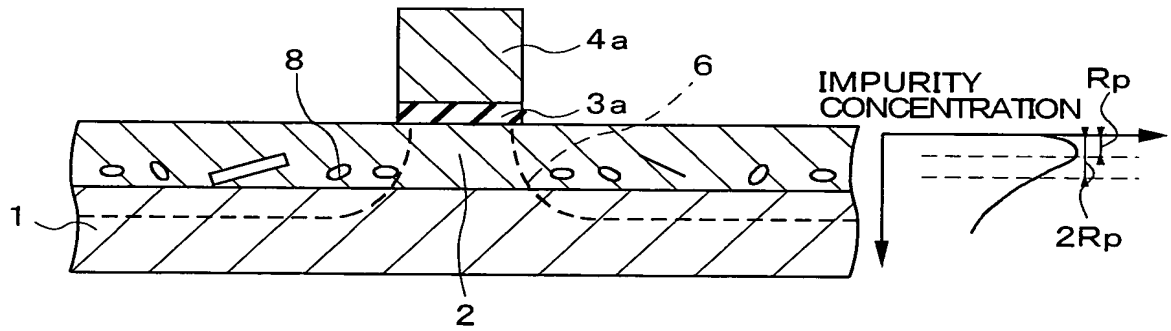
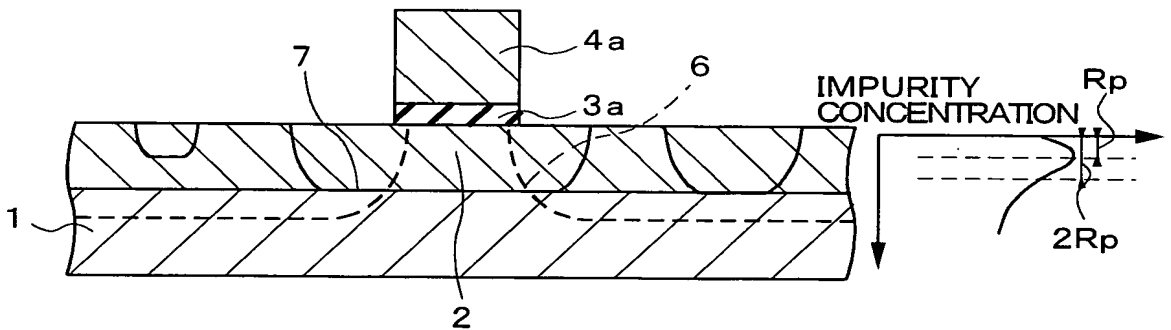


FIG. 36C



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